

KAF-16801

4096 (H) x 4096 (V) Full Frame CCD Image Sensor

Description

The KAF-16801 is a high performance area CCD (charge-coupled device) image sensor with 4096 (H) x 4096 (V) photo active pixels designed for a wide range of image sensing applications.

The sensor incorporates true two-phase CCD technology, simplifying the support circuits required to drive the sensor as well as reducing dark current without compromising charge capacity. The sensor also utilizes the TRUESENSE Transparent Gate Electrode to improve sensitivity compared to the use of a standard front side illuminated polysilicon electrode.

Table 1. GENERAL SPECIFICATIONS

Parameter	Typical Value
Architecture	Full Frame CCD
Pixel Count	4096 (H) x 4096 (V)
Pixel Size	9.0 μm (H) x 9.0 μm (V)
Active Image Size	36.88 mm (H) x 36.88 mm (V) 52.1 mm (Diagonal) 645 1.3x Optical Format
Chip Size	38.60 mm (H) x 37.76 mm (V)
Optical Fill Factor	100%
Saturation Signal	100,000 electrons
Output Sensitivity	13 $\mu\text{V}/\text{e}^-$
Dark Current (Accumulation Model)	< 10 pA/cm ²
Dark Current Doubling Rate	6°C
Dynamic Range (Saturation Signal/Dark Noise)	76 dB
Quantum Efficiency (450, 550, 650 nm)	40%, 52%, 65%
Maximum Data Rate	10 MHz
Package	CERDIP Package (Sidebrazed)
Cover Glass	Clear

NOTE: Parameters above are specified at T = 25°C unless otherwise noted.



ON Semiconductor®

www.onsemi.com

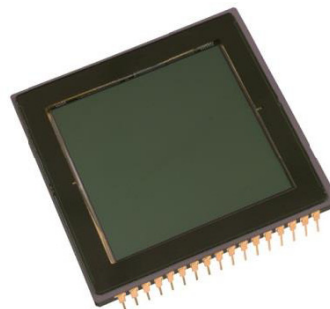


Figure 1. KAF-16801 Full Frame CCD Image Sensor

Features

- True Two Phase Full Frame Architecture
- TRUESENSE Transparent Gate Electrode for High Sensitivity
- Low Dark Current
- High Output Sensitivity

Application

- Scientific Imaging

ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

KAF-16801

ORDERING INFORMATION

Table 2. ORDERING INFORMATION – KAF-16801 IMAGE SENSOR

Part Number	Description	Marking Code
KAF-16801-AAA-DP-B1	Monochrome, No Microlens, CERDIP Package (Sidebrazed, CuW), Taped Clear Cover Glass (No Coatings), Grade 1	KAF-16801-AAA Serial Number
KAF-16801-AAA-DP-B2	Monochrome, No Microlens, CERDIP Package (Sidebrazed, CuW), Taped Clear Cover Glass (No Coatings), Grade 2	
KAF-16801-AAA-DP-AE	Monochrome, No Microlens, CERDIP Package (Sidebrazed, CuW), Taped Clear Cover Glass (No Coatings), Engineering Sample	

Table 3. ORDERING INFORMATION – EVALUATION SUPPORT

Part Number	Description
KEK-4H0082-KAF-160801-12-5	Evaluation Board (Complete Kit)

See the ON Semiconductor *Device Nomenclature* document (TND310/D) for a full description of the naming convention used for image sensors. For reference documentation, including information on evaluation kits, please visit our web site at www.onsemi.com.

DEVICE DESCRIPTION

Architecture

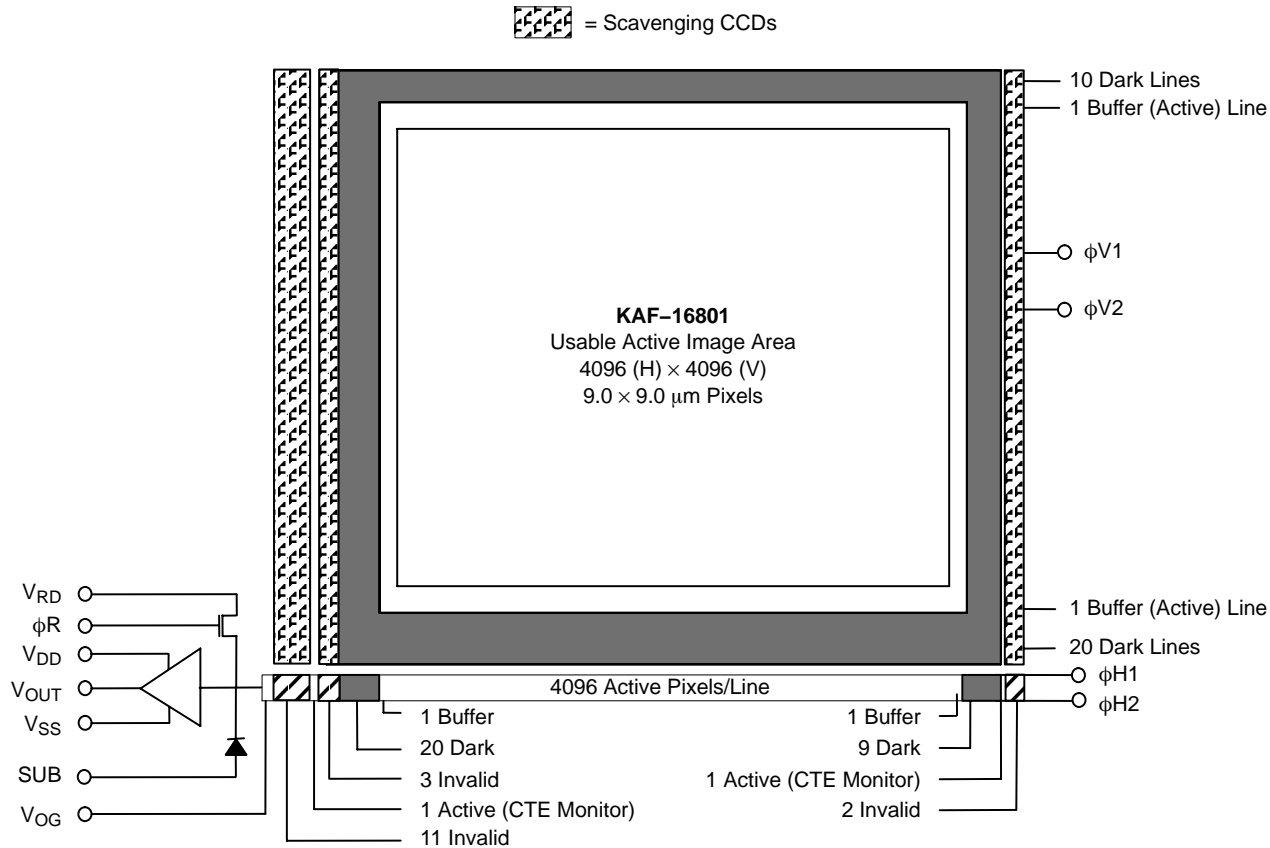


Figure 2. Block Diagram

The sensor consists of 4,127 parallel (vertical) CCD shift registers each 4,128 elements long. These registers act as both the photosensitive elements and as the transport circuits that allow the image to be sequentially read out of the sensor. The elements of these registers are arranged into a 4096 x 4096 photosensitive array surrounded by a light shielded dark reference of 29 columns and 30 rows. There is a buffer region of one photosensitive pixel surrounding the photosensitive region (one column at the beginning of a line, one column at the end of a line, one row at the beginning of a frame, and one row at the end of a frame). The parallel (vertical) CCD registers transfer the image one line at a time into a single 4,145 element (horizontal) CCD shift register. The horizontal register transfers the charge to a single output amplifier. The output amplifier is a three-stage source follower that converts the photo-generated charge to a voltage for each pixel.

Dark Reference Pixels

Surrounding the periphery of the device is a border of light shielded pixels. This includes 20 leading and 10 trailing pixels on every line excluding the inactive and photosensitive buffer pixels. There are also 20 full dark lines at the start of every frame and 10 full dark lines at the end of each frame. Under normal circumstances, these dark reference pixels do not respond to light. However, the pixels in close proximity to an active pixel can scavenge signal depending on light intensity and wavelength and therefore will not represent the true dark signal.

Output Structure

Charge presented to the floating diffusion (FD) is converted into a voltage and current amplified in order to drive off-chip loads. The resulting voltage change seen at the output is linearly related to the amount of charge placed on

FD. Once the signal has been sampled by the system electronics, the reset gate (ϕ_R) is clocked to remove the signal and FD is reset to the potential applied by V_{RD} . More signal at the floating diffusion reduces the voltage seen at the output pin. In order to activate the output structure, an off-chip load must be added to the V_{OUT} pin of the device – see Figure 3.

Transfer Efficiency Test Pixels and Dummy Pixels

At the beginning of each line and at the end of each line are extra horizontal CCD pixels. These are a combination of pixels that are not associated with any vertical CCD register and two that are associated with extra photo active vertical CCDs. The two extra photo active vertical CCDs are provided to give an accurate photo generated signal that can be used to monitor the charge transfer efficiency in the serial (horizontal) register.

They are arranged as follows beginning with the first pixel in each line:

- 11 Dark, Inactive Pixels
- 1 Photoactive Test Pixel
- 3 Inactive Pixels
- 20 Dark Reference Pixels
- 1 Active Buffer Pixel
- 4,096 Photoactive Pixels
- 1 Active Buffer Pixel
- 9 Dark Reference Pixels
- 1 Photoactive Test Pixel
- 2 Inactive Pixels

Image Acquisition

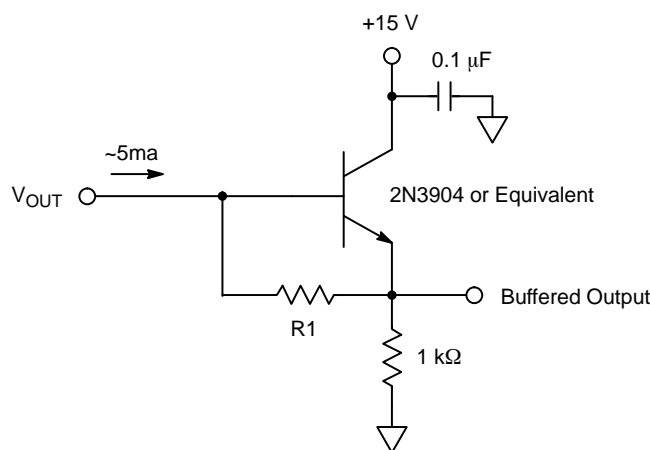
An electronic representation of an image is formed when incident photons falling on the sensor plane create electron-hole pairs within the sensor. These photon-induced electrons are collected locally by the formation of potential wells at each photogate or pixel site. The number of electrons collected is linearly dependent on light level and exposure time and non-linearly dependent on wavelength. When the pixel's capacity is reached, excess electrons will leak into the adjacent pixels within the same column. This is termed blooming. During the integration period, the ϕ_{V1} and ϕ_{V2} register clocks are held at a constant (low) level. See Figure 8.

Charge Transport

Referring again to Figure 8 – Timing Diagrams, the integrated charge from each photogate is transported to the output using a two-step process. Each line (row) of charge is first transported from the vertical CCDs to the horizontal CCD register using the ϕ_{V1} and ϕ_{V2} register clocks. The horizontal CCD is presented a new line on the falling edge of ϕ_{V1} while ϕ_{H2} is held high. The horizontal CCDs then transport each line, pixel by pixel, to the output structure by alternately clocking the ϕ_{H1} and ϕ_{H2} pins in a complementary fashion. On each falling edge of ϕ_{H1} a new charge packet is transferred onto a floating diffusion and sensed by the output amplifier.

Horizontal Register

Output Structure



Notes:

1. For operation of up to 10 MHz.
2. The value of $R1$ depends on the desired output current according to the following formula: $R1 = 0.7 / I_{OUT}$.
3. The optimal output current depends on the capacitance that needs to be driven by the amplifier and the bandwidth required. 5 mA is recommended for capacitance of 12 pF and pixel rates up to 20 MHz.

Figure 3. Output Structure Load Diagram

Physical Description

Pin Description and Device Orientation

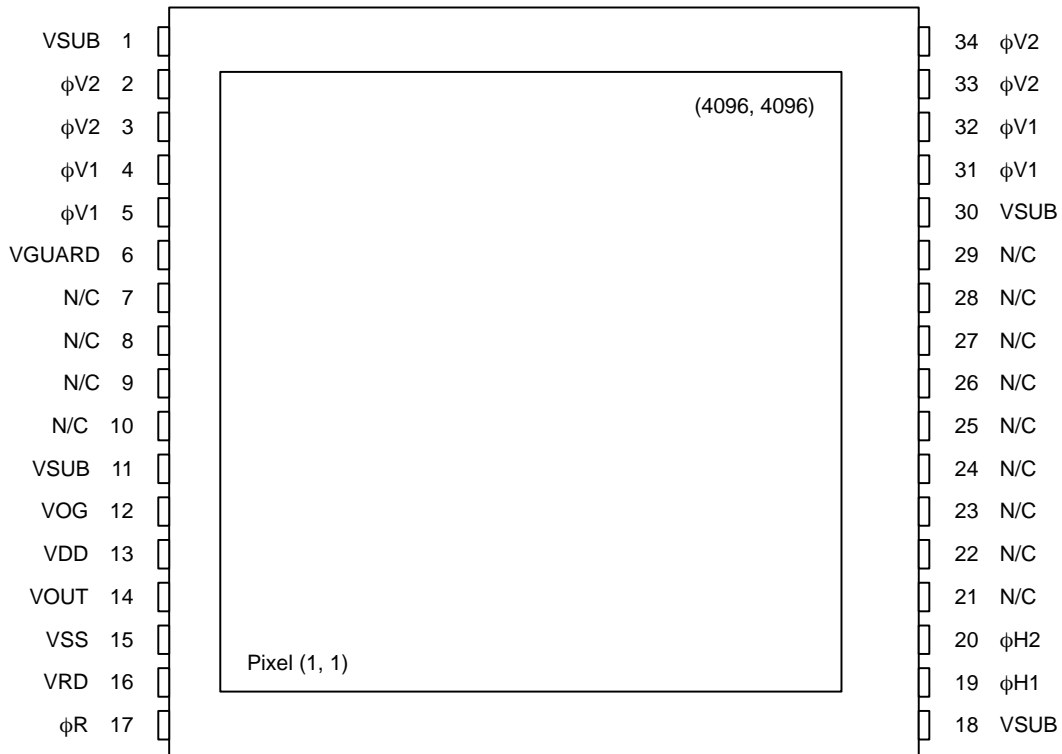


Figure 4. Pinout Diagram

Table 4. PIN DESCRIPTION

Pin	Name	Description
1	VSUB	Substrate (Ground)
2	$\phi V2$	Vertical CCD Clock – Phase 2
3	$\phi V2$	Vertical CCD Clock – Phase 2
4	$\phi V1$	Vertical CCD Clock – Phase 1
5	$\phi V1$	Vertical CCD Clock – Phase 1
6	VGUARD	Guard Ring
7	N/C	No Connection (Open Pin)
8	N/C	No Connection (Open Pin)
9	N/C	No Connection (Open Pin)
10	N/C	No Connection (Open Pin)
11	VSUB	Substrate (Ground)
12	VOG	Output Gate
13	VDD	Amplified Supply
14	VOUT	Video Output
15	VSS	Amplifier Supply Return
16	VRD	Reset Drain
17	ϕR	Reset Clock

Pin	Name	Description
18	VSUB	Substrate (Ground)
19	$\phi H1$	Horizontal CCD Clock – Phase 1
20	$\phi H2$	Horizontal CCD Clock – Phase 2
21	N/C	No Connection (Open Pin)
22	N/C	No Connection (Open Pin)
23	N/C	No Connection (Open Pin)
24	N/C	No Connection (Open Pin)
25	N/C	No Connection (Open Pin)
26	N/C	No Connection (Open Pin)
27	N/C	No Connection (Open Pin)
28	N/C	No Connection (Open Pin)
29	N/C	No Connection (Open Pin)
30	VSUB	Substrate (Ground)
31	$\phi V1$	Vertical CCD Clock – Phase 1
32	$\phi V1$	Vertical CCD Clock – Phase 1
33	$\phi V2$	Vertical CCD Clock – Phase 2
34	$\phi V2$	Vertical CCD Clock – Phase 2

IMAGING PERFORMANCE

Table 5. TYPICAL OPERATIONAL CONDITIONS

(All values measured at 25°C, and nominal operating conditions. These parameters exclude defective pixels.)

Description	Symbol	Min.	Nom.	Max.	Units	Notes	Verification Plan
Saturation Signal Vertical CCD Capacity Horizontal CCD Capacity Output Node Capacity	N_{SAT}	– 90,000 –	100,000 200,000 180,000	100,000 – 250,000	e^-/pix	1	Design ¹²
Photoresponse Non-Linearity	PRNL	–	1	2	%	2	Design ¹²
Photoresponse Non-Uniformity	PRNU	–	1	3	%	3, 10	Die ¹¹
Dark Signal	J_{DARK}	– –	18 3.5	50 10	$e^-/pix/sec$ $\mu A/cm^2$	4	Die ¹¹
Dark Signal Doubling Temperature		5	6.3	7.5	°C		Design ¹²
Dark Signal Non-Uniformity	DSNU	–	18	50	$e^-/pix/sec$	5, 10	Die ¹¹
Dynamic Range	DR	73	76	–	dB	6	Design ¹²
Charge Transfer Efficiency	CTE	0.99997	0.99999	–			Die ¹¹
Output Amplifier DC Offset	V_{ODC}	$V_{RD} - 3.0$	$V_{RD} - 2.5$	$V_{RD} - 2.0$	V	7	Die ¹¹
Output Amplifier Bandwidth	f_{-3dB}	–	140	–	MHz	8	Design ¹²
Output Amplifier Sensitivity	V_{OUT}/N_{e^-}	12.5	13	14	$\mu V/e^-$		Design ¹²
Output Amplifier Output Impedance	Z_{OUT}	–	130	–	Ω		Design ¹²
Noise Floor	n_{e^-}	–	15	20	electrons	9	Die ¹¹

1. For pixel binning applications, electron capacity up to 270,000 can be achieved with modified CCD inputs. Each sensor may have to be optimized individually for these applications. Some performance parameters may be compromised to achieve the largest signals.
2. Worst case deviation from straight line fit, between 1% and 90% of V_{SAT} .
3. One Sigma deviation of a 128×128 sample when CCD illuminated uniformly.
4. Average of all pixels with no illumination at 25°C.
5. Average dark signal of any of 32×32 blocks within the sensor (each block is 128×128 pixels).
6. $20 \log(N_{SAT} / n_{e^-})$ at nominal operating frequency and 25°C.
7. Video level offset with respect to ground.
8. Assumes 10 pF off-chip load.
9. Output amplifier noise at 25°C, operating at pixel frequency up to 2 MHz, bandwidth = 20 MHz, $t_{INT} = 0$, and no dark current shot noise.
10. Specification excludes region [1, 1, 400, 400]. See Dark Current Non-uniformity.
11. A parameter that is measured on every sensor during production testing.
12. A parameter that is quantified during the design verification activity.

TYPICAL PERFORMANCE CURVES

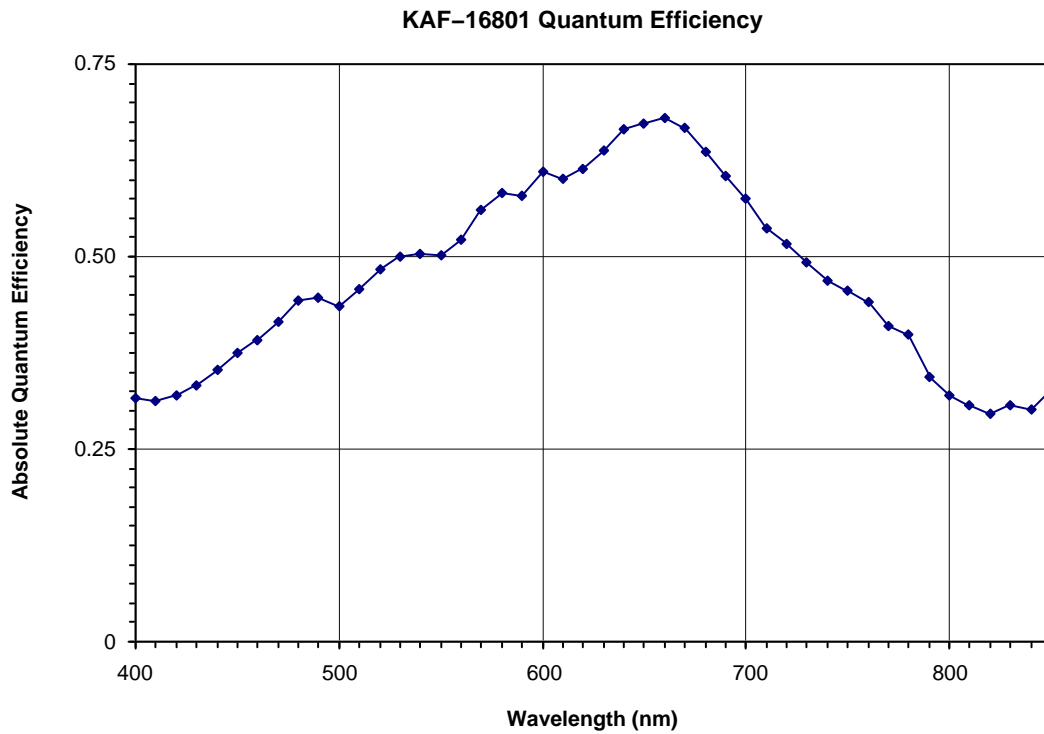


Figure 5. Typical Spectral Response

Dark Current Non-Uniformity

The photoresponse non-uniformity specification and the dark signal non-uniformity specification of the sensor both exclude the region that is [1, 1, 400, 400]. The reason for this exclusion is that when the sensor is running with V_{DD} always on, and the integration times are greater than 100 msec, a non-uniformity will become evident surrounding the first pixel. This non-uniformity is a result of

the output amplifier emitting light into the photoactive area (see Figure 9). The elevated dark signal in this region typically ranges from $30 \text{ e}^-/\text{pix}/\text{sec}$ to $100 \text{ e}^-/\text{pix}/\text{sec}$, depending on the part, and is independent of temperature. If V_{DD} is switched to 0 V at least 10 μsec after the last pixel is read out, and switched back to full value 10 μsec before the first pixel of the next frame, the effect of the amplifier glow will be eliminated (see Figure 10).

DEFECT DEFINITIONS

Table 6. SPECIFICATIONS (All defect tests performed at T = 25°C)

Classification	Point Defects	Cluster Defects	Maximum Cluster Size	Column Defects	Maximum Column Width
C1	≤ 60	≤ 8	8	4	1
C2	≤ 120	≤ 16	8	10	1
C3	≤ 240	≤ 32	15	20	2

Point Defects

Dark: A pixel which deviates by more than 6% from neighboring pixels when illuminated to 70% of saturation.

Bright: A pixel with a dark current > 7,000 e⁻/pixel/sec at 25°C.

Cluster Defect

A grouping of not more than 5 adjacent point defects.

Column Defect

A grouping of > 5 contiguous point defects along a single column.

A column containing a pixel with dark current > 20,000 e⁻/pixel/sec.

A column that does not meet the CTE specification for all exposures less than the specified Max sat. signal level and greater than 2 ke⁻.

A column which contains a pixel that loses > 250 e⁻ under 2 ke⁻ illumination.

Neighboring Pixels

The surrounding 128 × 128 pixels or ±64 columns/rows.

Defect Separation

Column and cluster defects are separated by no less than 2 pixels in any direction (excluding single pixel defects).

Defect Region Exclusion

Defect region excludes the outer 2 rows and columns at each side/end of the sensor.

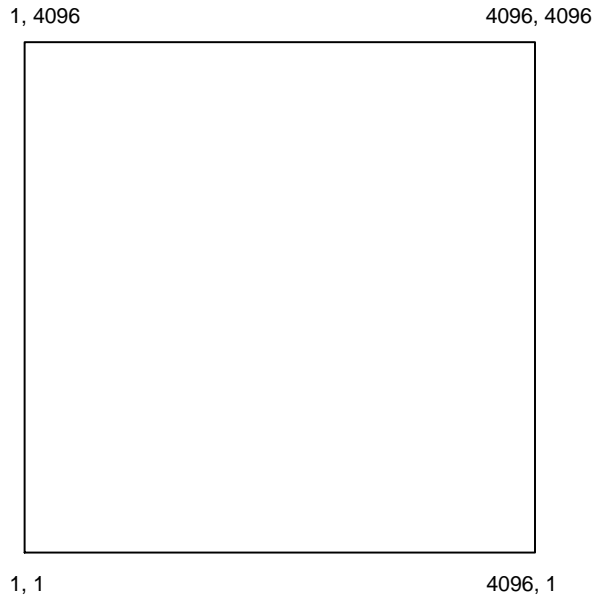


Figure 6. Active Pixel Region

OPERATION

Table 7. ABSOLUTE MAXIMUM RATINGS

Description	Symbol	Minimum	Maximum	Units	Notes
Diode Pin Voltages	V_{DIODE}	0	20	V	1, 2
Gate Pin Voltages – Type 1	V_{GATE1}	-16	16	V	1, 3
Gate Pin Voltages – Type 2	V_{GATE2}	0	16	V	1, 4
Inter-Gate Voltages	V_{G-G}	-	16	V	5
Output Bias Current	I_{OUT}	-	-10	mA	6
Output Load Capacitance	C_{LOAD}	-	15	pF	6
Storage Temperature	T	-50	70	°C	
Humidity	RH	5	90	%	7

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Referenced to pin VSUB.
2. Includes pins: VRD, VDD, VSS, VOUT, VGUARD.
3. Includes pins: $\phi V1$, $\phi V2$, $\phi H1$, $\phi H2$.
4. Includes pins: ϕR , VOG.
5. Voltage difference between overlapping gates. Includes: $\phi V1$ to $\phi V2$, $\phi H1$ to $\phi H2$, $\phi V1$ to $\phi H2$, $\phi H1$ to VOG.
6. Avoid shorting output pins to ground or any low impedance source during operation.
7. T = 25°C. Excessive humidity will degrade MTF.

Table 8. DC BIAS OPERATING CONDITIONS

Description	Symbol	Minimum	Nominal	Maximum	Units	Maximum DC Current (mA)	Notes
Reset Drain	V_{RD}	11.0	12.0	12.25	V	0.01	
Output Amplifier Return	V_{SS}	1.5	2.0	2.5	V	0.45	
Output Amplifier Supply	V_{DD}	14.5	15.0	17.0	V	I_{OUT}	
Substrate	V_{SUB}	0	0	0	V	0.01	
Output Gate	V_{OG}	4.5	5.0	5.2	V	0.01	
Guard Ring	V_{LG}	9.0	10.0	12.0	V	0.01	
Video Output Current	I_{OUT}	-3.5	-5.0	-10.0	mA		1

1. An output load sink must be applied to V_{OUT} to activate output amplifier – see Figure 3.

AC Operating Conditions

Table 9. CLOCK LEVELS

Description	Symbol	Level	Minimum	Nominal	Maximum	Units	Effective Capacitance
Vertical CCD Clock – Phase 1	$\phi V1$	Low	-9.0	-8.5	-8.3	V	250 nF (All $\phi V1$ Pins)
Vertical CCD Clock – Phase 1	$\phi V1$	High	$\phi V1$ Low + 10.5	2.0	$\phi V1$ Low + 10.5	V	250 nF (All $\phi V1$ Pins)
Vertical CCD Clock – Phase 2	$\phi V2$	Low	-9.0	-8.5	-8.3	V	250 nF (All $\phi V2$ Pins)
Vertical CCD Clock – Phase 2	$\phi V2$	High	$\phi V2$ Low + 10.5	2.0	$\phi V2$ Low + 10.5	V	250 nF (All $\phi V2$ Pins)
Horizontal CCD Clock – Phase 1	$\phi H1$	Low	-2.5	-2.5	-1.8	V	500 pF
Horizontal CCD Clock – Phase 1	$\phi H1$	High	$\phi H1$ Low + 10.5	2.0	$\phi H1$ Low + 10.5	V	500 pF
Horizontal CCD Clock – Phase 2	$\phi H2$	Low	-2.5	-2.5	-1.8	V	300 pF
Horizontal CCD Clock – Phase 2	$\phi H2$	High	$\phi H2$ Low + 10.5	2.0	$\phi H2$ Low + 10.5	V	300 pF
Reset Clock	ϕR	Low	3.0	5.0	5.5	V	10 pF
Reset Clock	ϕR	High	9.5	10.0	10.5	V	10 pF

1. All pins draw less than 10 μ A DC current.
2. Capacitance include gate to V_{SUB} and gate to gate ($\phi V1$ - $\phi V2$, $\phi H1$ - $\phi H2$).

TIMING

Table 10. REQUIREMENTS AND CHARACTERISTICS

Description	Symbol	Minimum	Nominal	Maximum	Units	Notes
ϕ H1, ϕ H2 Clock Frequency	f_H	–	8	15	MHz	1, 2, 3
ϕ V1, ϕ V2 Clock Frequency	F_V	–	25	25	MHz	1, 2, 3
Pixel Period (1 Count)	t_e	67	125	–	ns	
ϕ H1, ϕ H2 Set-up Time	$t_{\phi HS}$	0.5	1	–	μ s	
ϕ V1, ϕ V2 Clock Pulse Width	$t_{\phi V}$	40	40	–	μ s	2
ϕ V1, ϕ V2 Clock Pulse Overlap	t_{OVRLP}	20	20	–	μ s	
Reset Clock Width	$t_{\phi R}$	10	20	–	ns	4
Readout Time	$t_{READOUT}$	1,398	2,390	–	ms	5
Integration Time	t_{INT}	–	–	–		6
Line Time	t_{LINE}	338.7	580	–	μ s	7

1. 50% duty cycle values.
2. CTE may degrade above the nominal frequency.
3. Rise and fall times (10/90% levels) should be limited to 5–10% of clock period. Cross-over of register clocks should be between 40–60% of amplitude.
4. ϕ R should be clocked continuously.
5. $t_{READOUT} = (4128 \cdot t_{LINE})$
6. Integration time is user specified. Longer integration times will degrade noise performance.
7. $t_{LINE} = (2 \cdot t_{\phi V}) - t_{OVRLP} + t_{\phi HS} + (4145 \cdot t_e) + t_e$.

Frame Timing

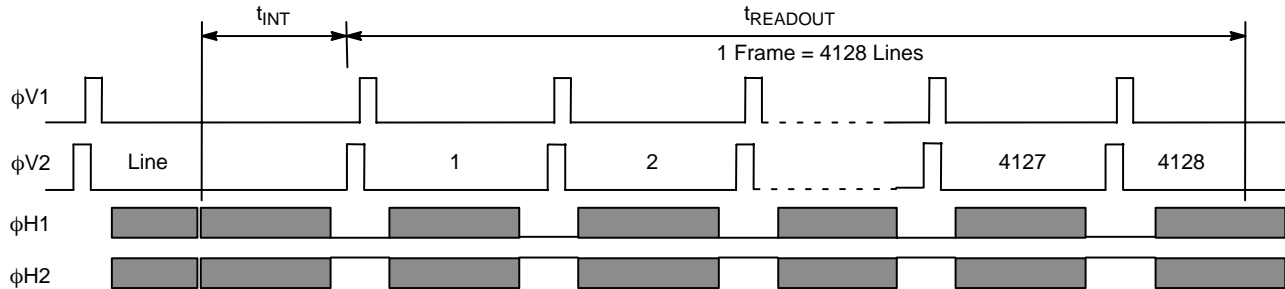


Figure 7. Frame Timing Diagram

Line Timing and Pixel Timing

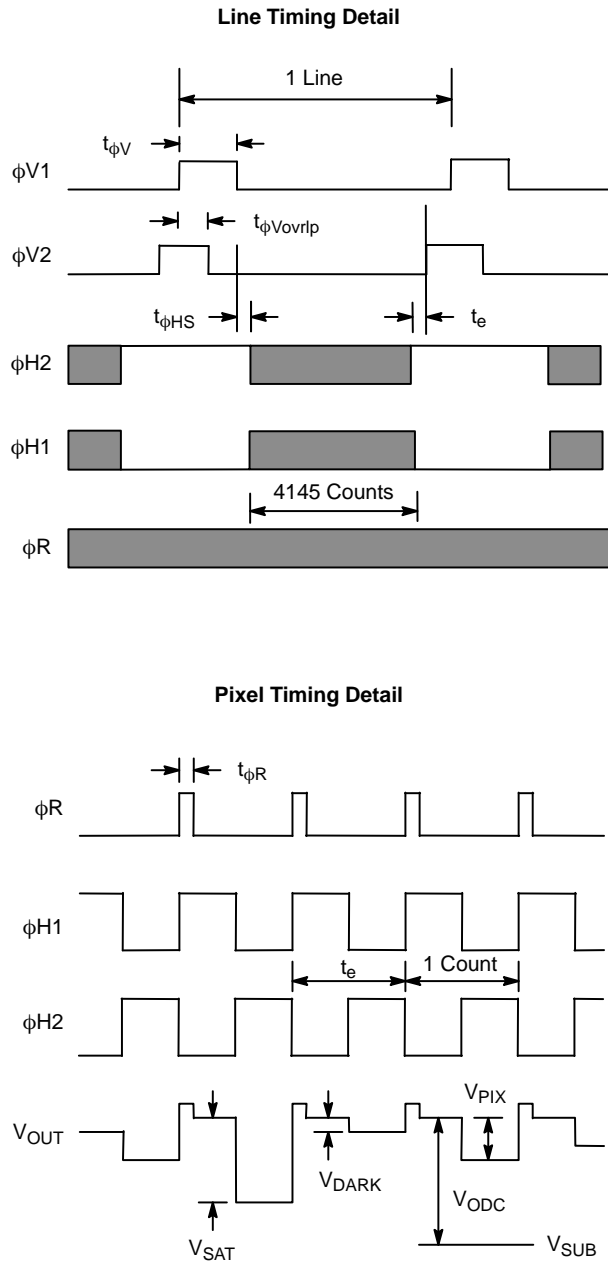
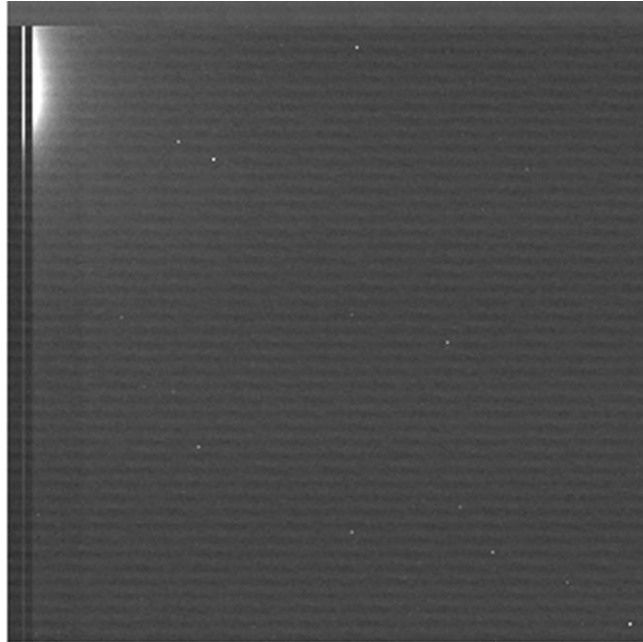
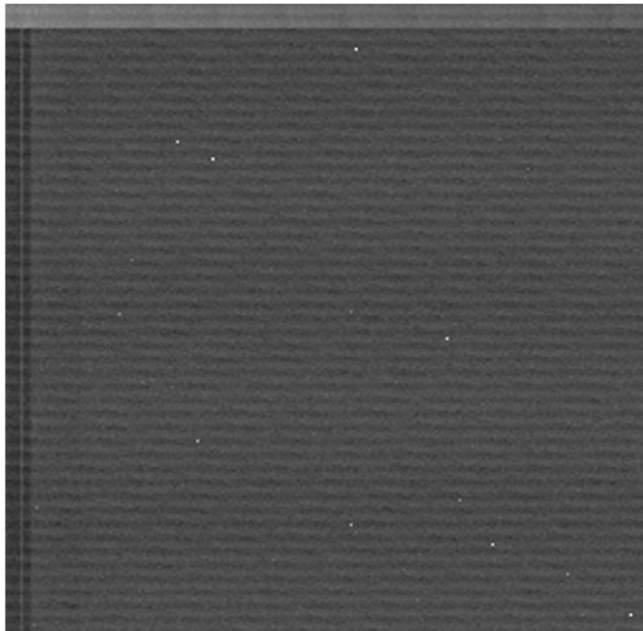


Figure 8. Line Timing and Pixel Timing



**Figure 9. Amplifier Glow – S11LE @-20C with 20 sec Integration @1 MHz
V_{DD} always ON (+15)**



**Figure 10. Amplifier Glow – S11LE @-20C with 20 sec Integration @1 MHz
V_{DD} OFF during Integration**

NOTE: Amplifier glow is suppressed by switching V_{DD} to 0 V during integration.

STORAGE AND HANDLING

Table 11. STORAGE CONDITIONS

Description	Symbol	Minimum	Maximum	Units	Notes
Storage Temperature	T _{ST}	-20	100	°C	1
Operating Temperature	T _{OP}	-60	60	°C	

1. Storage toward the maximum temperature will accelerate microlens degradation.

For information on ESD and cover glass care and cleanliness, please download the *Image Sensor Handling and Best Practices* Application Note (AN52561/D) from www.onsemi.com.

For information on soldering recommendations, please download the *Soldering and Mounting Techniques Reference Manual* (SOLDERRM/D) from www.onsemi.com.

For quality and reliability information, please download the *Quality & Reliability Handbook* (HBD851/D) from www.onsemi.com.

For information on device numbering and ordering codes, please download the *Device Nomenclature* technical note (TND310/D) from www.onsemi.com.

For information on Standard terms and Conditions of Sale, please download [Terms and Conditions](http://www.onsemi.com) from www.onsemi.com.

MECHANICAL INFORMATION

Completed Assembly

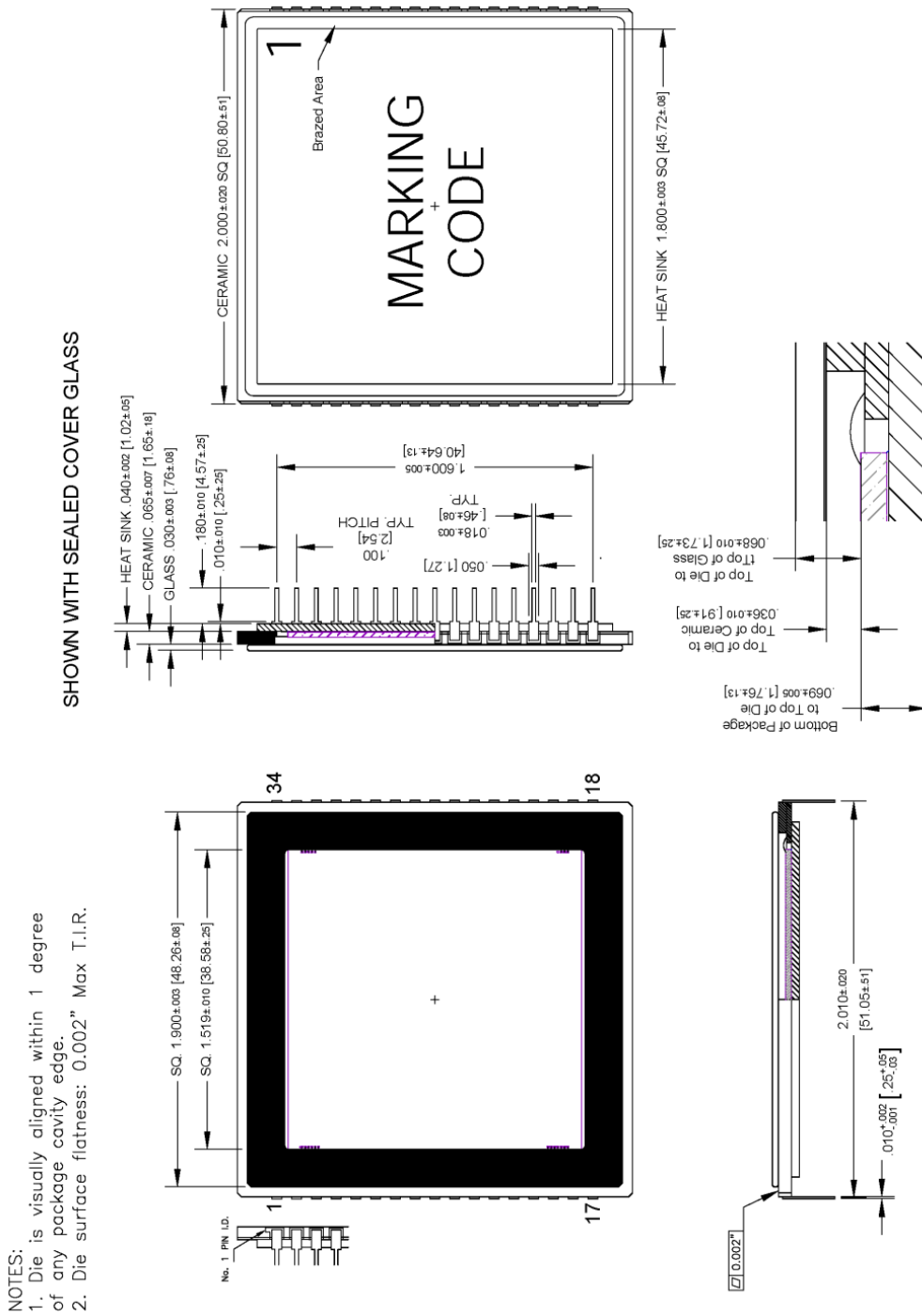


Figure 11. Completed Assembly (1 of 2)

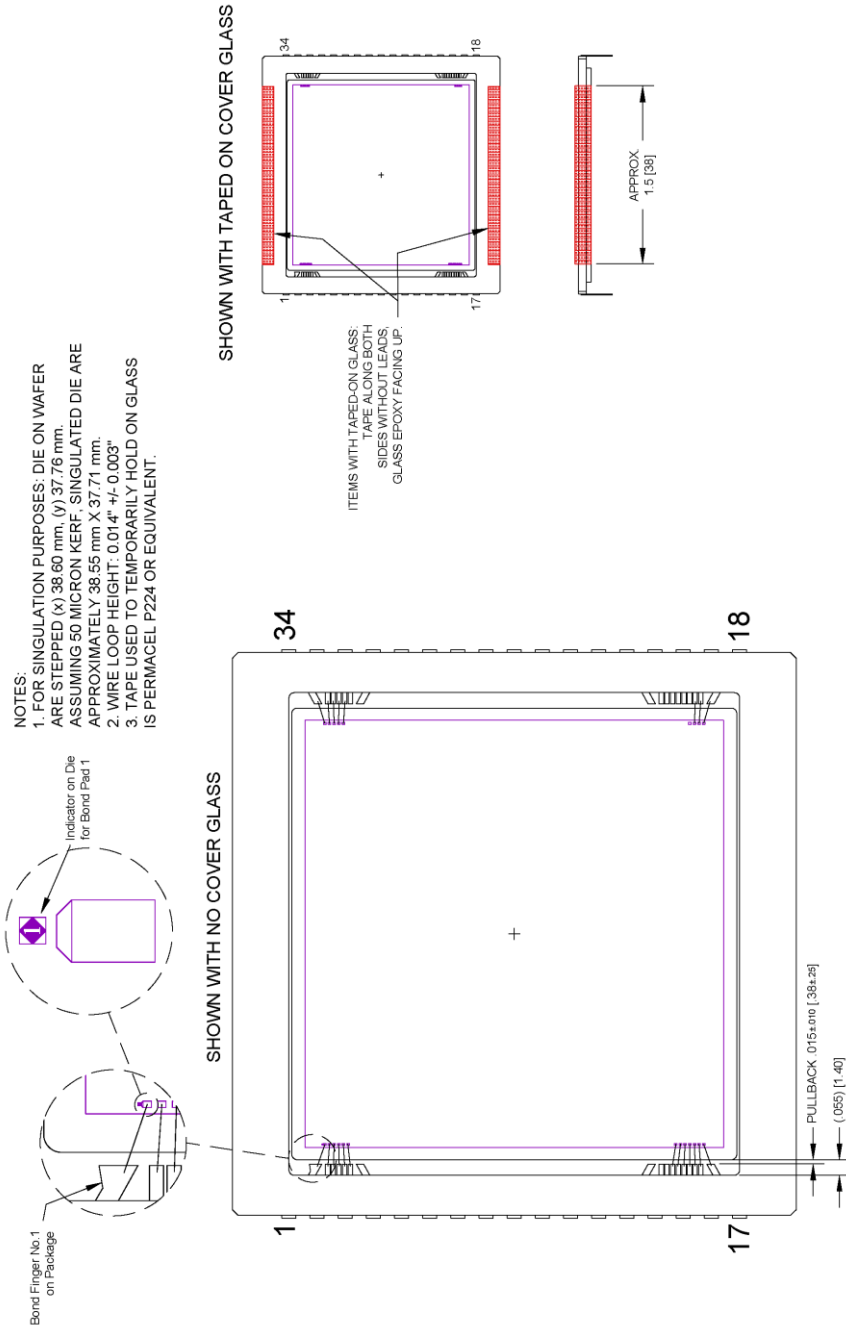



Figure 12. Completed Assembly (2 of 2)

ON Semiconductor and the  are registered trademarks of Semiconductor Components Industries, LLC (SCILLC) or its subsidiaries in the United States and/or other countries. SCILLC owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of SCILLC's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. SCILLC reserves the right to make changes without further notice to any products herein. SCILLC makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does SCILLC assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. "Typical" parameters which may be provided in SCILLC data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. SCILLC does not convey any license under its patent rights nor the rights of others. SCILLC products are not designed, intended, or authorized for use as components in systems intended for surgical implant into the body, or other applications intended to support or sustain life, or for any other application in which the failure of the SCILLC product could create a situation where personal injury or death may occur. Should Buyer purchase or use SCILLC products for any such unintended or unauthorized application, Buyer shall indemnify and hold SCILLC and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that SCILLC was negligent regarding the design or manufacture of the part. SCILLC is an Equal Opportunity/Affirmative Action Employer. This literature is subject to all applicable copyright laws and is not for resale in any manner.

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor
P.O. Box 5163, Denver, Colorado 80217 USA
Phone: 303-675-2175 or 800-344-3860 Toll Free USA/Canada
Fax: 303-675-2176 or 800-344-3867 Toll Free USA/Canada
Email: orderlit@onsemi.com

N. American Technical Support: 800-282-9855 Toll Free
USA/Canada
Europe, Middle East and Africa Technical Support:
Phone: 421 33 790 2910
Japan Customer Focus Center
Phone: 81-3-5817-1050

ON Semiconductor Website: www.onsemi.com
Order Literature: <http://www.onsemi.com/orderlit>
For additional information, please contact your local
Sales Representative



Стандарт Электрон Связь

Мы молодая и активно развивающаяся компания в области поставок электронных компонентов. Мы поставляем электронные компоненты отечественного и импортного производства напрямую от производителей и с крупнейших складов мира.

Благодаря сотрудничеству с мировыми поставщиками мы осуществляем комплексные и плановые поставки широчайшего спектра электронных компонентов.

Собственная эффективная логистика и склад в обеспечивает надежную поставку продукции в точно указанные сроки по всей России.

Мы осуществляем техническую поддержку нашим клиентам и предпродажную проверку качества продукции. На все поставляемые продукты мы предоставляем гарантию .

Осуществляем поставки продукции под контролем ВП МО РФ на предприятия военно-промышленного комплекса России , а также работаем в рамках 275 ФЗ с открытием отдельных счетов в уполномоченном банке. Система менеджмента качества компании соответствует требованиям ГОСТ ISO 9001.

Минимальные сроки поставки, гибкие цены, неограниченный ассортимент и индивидуальный подход к клиентам являются основой для выстраивания долгосрочного и эффективного сотрудничества с предприятиями радиоэлектронной промышленности, предприятиями ВПК и научно-исследовательскими институтами России.

С нами вы становитесь еще успешнее!

Наши контакты:

Телефон: +7 812 627 14 35

Электронная почта: sales@st-electron.ru

Адрес: 198099, Санкт-Петербург,
Промышленная ул, дом № 19, литера Н,
помещение 100-Н Офис 331